

(19) 世界知的所有権機関
国際事務局



(43) 国際公開日
2003 年 5 月 30 日 (30.05.2003)

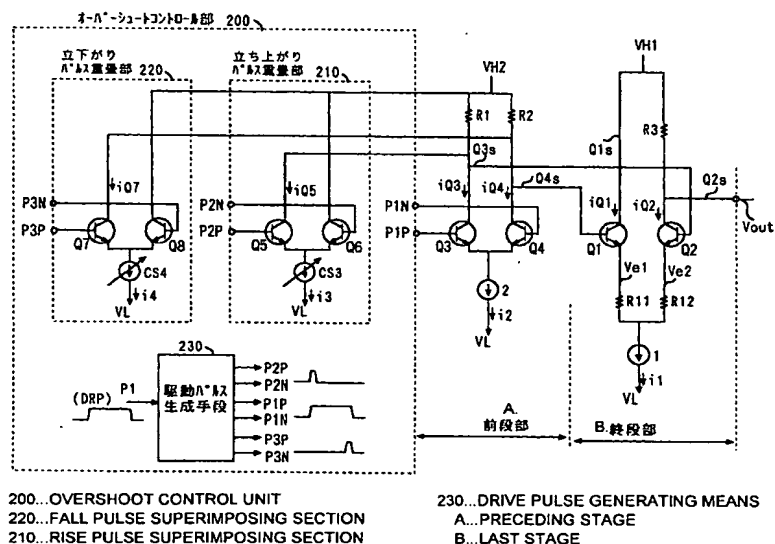
PCT

(10) 国際公開番号
WO 03/044550 A1

- (51) 国際特許分類⁷: G01R 31/28 [JP/JP]; 〒179-0071 東京都練馬区旭町一丁目32番1号 Tokyo (JP).
- (21) 国際出願番号: PCT/JP02/12123
- (22) 国際出願日: 2002 年 11 月 20 日 (20.11.2002)
- (25) 国際出願の言語: 日本語
- (26) 国際公開の言語: 日本語
- (30) 優先権データ:
特願 2001-354217
2001 年 11 月 20 日 (20.11.2001) JP
- (71) 出願人 (米国を除く全ての指定国について): 株式会社アドバンテスト (ADVANTEST CORPORATION)
- (72) 発明者; および
(75) 発明者/出願人 (米国についてのみ): 小島 昭二 (KOJIMA, Shoji) [JP/JP]; 〒370-0718 群馬県邑楽郡明和町大輪336-1 株式会社アドバンテスト内 Gunma (JP).
- (81) 指定国 (国内): JP, US.
- 添付公開書類:
— 国際調査報告書
- 2文字コード及び他の略語については、定期発行される各PCTガゼットの巻頭に掲載されている「コードと略語のガイダンスノート」を参照。

(54) Title: SEMICONDUCTOR TESTER

(54) 発明の名称: 半導体試験装置



INTERNATIONAL SEARCH REPORT

International application No.
PCT/JP02/12123

A. CLASSIFICATION OF SUBJECT MATTER

Int.Cl⁷ G01R31/28

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)
Int.Cl⁷ G01R31/28, H04L25/03

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched
Jitsuyo Shinan Koho 1922-1996 Jitsuyo Shinan Toroku Koho 1996-2003
Kokai Jitsuyo Shinan Koho 1971-2003 Toroku Jitsuyo Shinan Koho 1994-2003

Electronic data base consulted during the international search (name of data base and, where practicable, search terms used)

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category*	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	JP 8-242151 A (Hitachi, Ltd.), 17 September, 1996 (17.09.96), Full text; all drawings (Family: none)	1-4
X	JP 4-189051 A (Hitachi, Ltd.), 07 July, 1992 (07.07.92), Full text; all drawings (Family: none)	1, 2

☐ Further documents are listed in the continuation of Box C. ☐ See patent family annex.

* Special categories of cited documents:	"T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
"A" document defining the general state of the art which is not considered to be of particular relevance	"X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
"E" earlier document but published on or after the international filing date	"Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art
"L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)	"&" document member of the same patent family
"O" document referring to an oral disclosure, use, exhibition or other means	
"P" document published prior to the international filing date but later than the priority date claimed	

Date of the actual completion of the international search
18 February, 2003 (18.02.03)

Date of mailing of the international search report
04 March, 2003 (04.03.03)

Name and mailing address of the ISA/
Japanese Patent Office

Authorized officer

Facsimile No.

Telephone No.